## **Power MOSFET**

# 30 V, 100 A, Single N-Channel, SO-8 FL

#### **Features**

- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Capacitance to Minimize Driver Losses
- Optimized Gate Charge to Minimize Switching Losses
- Thermally Enhanced SO8 Package
- These are Pb-Free Device

### **Applications**

- CPU Power Delivery
- DC-DC Converters
- Low Side Switching

### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise stated)

Para	Symbol	Value	Unit		
Drain-to-Source Voltage			$V_{DSS}$	30	V
Gate-to-Source Vol	Gate-to-Source Voltage			±16	V
Continuous Drain		T <sub>A</sub> = 25°C	Ι <sub>D</sub>	20.3	Α
Current R <sub>θJA</sub> (Note 1)		T <sub>A</sub> = 85°C		14.6	
Power Dissipation $R_{\theta JA}$ (Note 1)		T <sub>A</sub> = 25°C	P <sub>D</sub>	2.25	W
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	32.8	Α
Current R <sub>θJA</sub> ≤ 10 sec		T <sub>A</sub> = 85°C		23.7	
Power Dissipation $R_{\theta JA,} t \leq 10 \text{ sec}$	Steady	T <sub>A</sub> = 25°C	P <sub>D</sub>	5.90	W
Continuous Drain	State	T <sub>A</sub> = 25°C	I <sub>D</sub>	12.7	Α
Current $R_{\theta JA}$ (Note 2)		T <sub>A</sub> = 85°C		9.2	
Power Dissipation R <sub>θJA</sub> (Note 2)		T <sub>A</sub> = 25°C	P <sub>D</sub>	0.89	W
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	100	Α
Current R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 85°C		72	
Power Dissipation $R_{\theta JC}$ (Note 1)		T <sub>C</sub> = 25°C	P <sub>D</sub>	55.5	W
Pulsed Drain Current	t <sub>p</sub> =10μs	T <sub>A</sub> = 25°C	I <sub>DM</sub>	200	Α
Current limited by pa	ckage	T <sub>A</sub> = 25°C	I <sub>Dmaxpkg</sub>	100	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C
Source Current (Body Diode)			I <sub>S</sub>	55	Α
Drain to Source dV/dt			dV/dt	6	V/ns
Single Pulse Drain-to-Source Avalanche Energy ( $V_{DD}$ = 50 V, $V_{GS}$ = 10 V, $I_{L}$ = 37 $A_{pk}$ , $L$ = 0.3 mH, $R_{G}$ = 25 $\Omega$ )			EAS	205	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

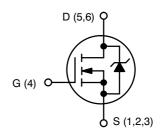
Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.



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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX		
30 V	3.4 m $\Omega$ @ 10 V	100 A		
	5.1 mΩ @ 4.5 V	100 A		



**N-CHANNEL MOSFET** 



### SO-8 FLAT LEA CASE 488AA STYLE 1



**MARKING** 

A = Assembly Location

Y = Year WW = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTMFS4846NT1G	SO-8FL (Pb-Free)	1500 / Tape & Reel
NTMFS4846NT3G	SO-8FL (Pb-Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

1

<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case (Drain)	$R_{ heta JC}$	2.25	
Junction-to-Ambient - Steady State (Note 1)	$R_{ heta JA}$	55.6	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ heta JA}$	140.8	C/VV
Junction-to-Ambient - t ≤ 10 sec	$R_{ heta JA}$	21.2	

- Surface-mounted on FR4 board using 1 sq-in pad, 1 oz Cu.
   Surface-mounted on FR4 board using the minimum recommended pad size.

### FLECTRICAL CHARACTERISTICS (T. - 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•			•		•	•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				25		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 24 V	T <sub>J</sub> = 25 °C			1	μΑ
			T <sub>J</sub> = 125°C			10	pa t
Gate-to-Source Leakage Current	$I_{GSS}$	$V_{DS} = 0 V, V_{GS}$	= ±16 V			±100	nA
ON CHARACTERISTICS (Note 3)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 250 μΑ	1.45	1.8	2.5	V
Negative Threshold Temperature Coefficient	$V_{GS(TH)}/T_J$				5.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V to 11.5 V	I <sub>D</sub> = 30 A		2.5	3.4	mΩ
			I <sub>D</sub> = 15 A		2.4		
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 30 A		3.8	5.1	
			I <sub>D</sub> = 15 A		3.8		
Forward Transconductance	9FS	V <sub>DS</sub> = 1.5 V, I <sub>D</sub> = 30 A			85		S
CHARGES AND CAPACITANCES	•			•		•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 12 V			3250		pF
Output Capacitance	C <sub>OSS</sub>				562		
Reverse Transfer Capacitance	C <sub>RSS</sub>				289		
Total Gate Charge	Q <sub>G(TOT)</sub>				21.8	32	1
Threshold Gate Charge	Q <sub>G(TH)</sub>				3.2		1 _
Gate-to-Source Charge	Q <sub>GS</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = -2.5 \text{ V}$	15 V; I <sub>D</sub> = 30 A		8.1		nC
Gate-to-Drain Charge	$Q_{GD}$	1			7.4		1
Total Gate Charge	Q <sub>G(TOT)</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 30 A			53		nC
SWITCHING CHARACTERISTICS (Note 4)	•						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			18.9		
Rise Time	t <sub>r</sub>				34		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>				24.6		ns
Fall Time	t <sub>f</sub>			-	9.4	<b>!</b>	1

- 3. Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%. 4. Switching characteristics are independent of operating junction temperatures.

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS (N	ote 4)						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 11.5 V, $V_{DS}$ = 15 V, $I_{D}$ = 15 A, $R_{G}$ = 3.0 $\Omega$			10.7		- ns
Rise Time	t <sub>r</sub>				18.9		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				34.2		
Fall Time	t <sub>f</sub>				7.1		
DRAIN-SOURCE DIODE CHARACT	ERISTICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 30 A	T <sub>J</sub> = 25°C		0.8	1.0	
			T <sub>J</sub> = 125°C		0.66		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 30 \text{ A}$			21.6		ns
Charge Time	t <sub>a</sub>				11.4		
Discharge Time	t <sub>b</sub>				10.2		
Reverse Recovery Charge	Q <sub>RR</sub>				8.5		nC
PACKAGE PARASITIC VALUES							
Source Inductance	L <sub>S</sub>	T <sub>A</sub> = 25°C			0.65		nΗ
Drain Inductance	L <sub>D</sub>				0.005		
Gate Inductance	L <sub>G</sub>				1.84		
Gate Resistance	$R_{G}$				1.4		Ω

<sup>3.</sup> Pulse Test: pulse width  $\leq$  300  $\mu$ s, duty cycle  $\leq$  2%.

### **TYPICAL CHARACTERISTICS**

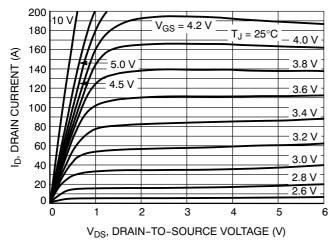


Figure 1. On-Region Characteristics

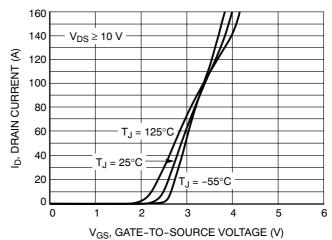


Figure 2. Transfer Characteristics

<sup>4.</sup> Switching characteristics are independent of operating junction temperatures.

### TYPICAL CHARACTERISTICS

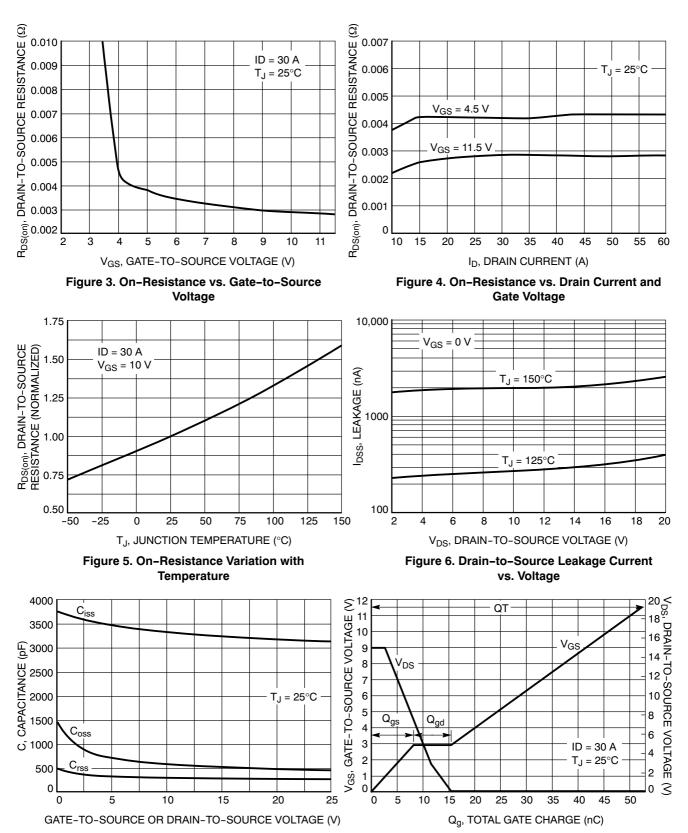


Figure 7. Capacitance Variation

Figure 8. Gate-to-Source and Drain-to-Source Voltage vs. Total Charge

### **TYPICAL CHARACTERISTICS**

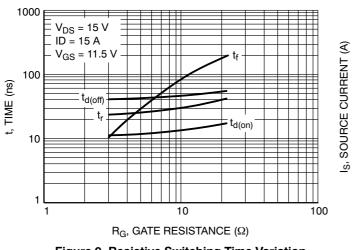


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

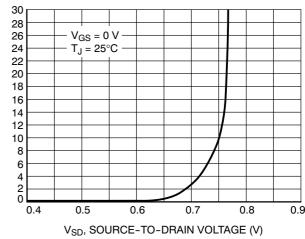


Figure 10. Diode Forward Voltage vs. Current

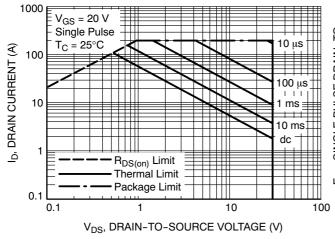


Figure 11. Maximum Rated Forward Biased Safe Operating Area

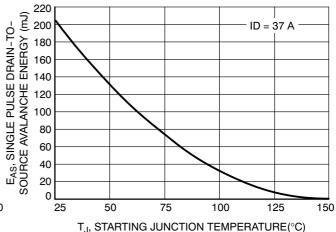


Figure 12. Maximum Avalanche Energy vs. Starting Junction Temperature

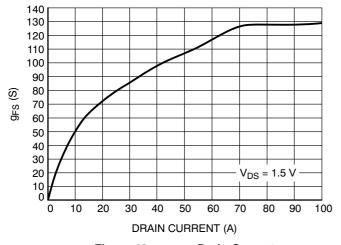


Figure 13. g<sub>FS</sub> vs. Drain Current

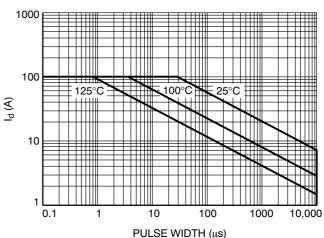
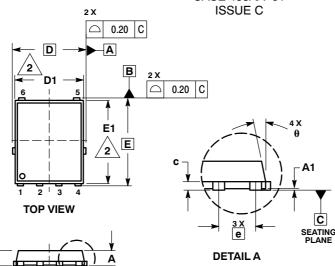


Figure 14. I<sub>d</sub> vs. Pulse Width

#### PACKAGE DIMENSIONS

## **DFN6 5x6, 1.27P (SO8 FL)** CASE 488AA-01



STYLE 1: PIN 1. SOURCE 2. SOURCE

3. SOURCE 4. GATE

5. DRAIN 6. DRAIN

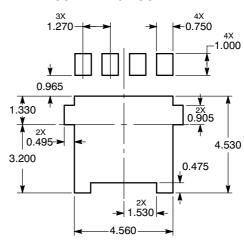
**DETAIL A** 

#### NOTES

- DIMENSIONING AND TOLERANCING PER
   ASME VIA EM 1004
- ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE

	MILLIMETERS						
ДΙΜ	MIN	MAX					
A		1.00	1.10				
	0.90	1.00					
A1	0.00		0.05				
b	0.33	0.41	0.51				
С	0.23	0.28	0.33				
D		5.15 BSC					
D1	4.50	4.90	5.10				
D2	3.50		4.22				
Е		6.15 BSC	;				
E1	5.50	5.80	6.10				
E2	3.45		4.30				
е		1.27 BSC	;				
G	0.51	0.61	0.71				
K	0.51						
L	0.51	0.61	0.71				
L1	0.05	0.17	0.20				
M	3.00	3.40	3.80				
θ	0 °		12 °				

#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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